

Amendments to the Claims

This listing of claims will replace all prior versions, and listings, of claims in the application.

1. (Canceled).
2. (New) A method of testing a device under test comprising:
 - (a) providing a coherent beam of light from a light source having a first wavelength;
 - (b) imposing said coherent beam of light on a test device over a spatial region within said test device greater than said first wavelength, wherein said test device has a first state;
 - (c) imposing said beam of light on said test device over a spatial region within said test device greater than said first wavelength, wherein said test device has a second state;
 - (d) obtaining data resulting from the interference of said first beam and said second beam within said device under test representative of the voltages within said region;
 - (e) wherein said first state is at a first voltage potential, and wherein said second state is at a second voltage potential different from said first voltage potential.
3. (New) The method of claim 2 wherein said beam is provided from a laser.
4. (New) The method of claim 2 wherein said coherent light is infrared.
5. (New) The method of claim 3 wherein said test device is silicon.
6. (New) The method of claim 2 wherein said interference of said first beam and said second beam is within said test device.

7. (New) The method of claim 2 wherein said interference of said first beam and said second beam is calculated.

8. (New) The method of claim 1 wherein said first state of refraction is without a voltage being applied thereto.